



UT1D2P10M

Preliminary

Power MOSFET

-1.2A, -100V P-CHANNEL ENHANCEMENT MODE

DESCRIPTION

The UTC **UT1D2P10M** is P-Channel enhancement mode Power MOSFET, designed in serried ranks with fast switching speed, low on-resistance and favorable stabilization.

Used in commercial and industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

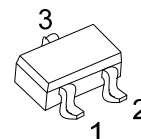
FEATURES

* $R_{DS(ON)} \leq 0.95 \Omega$ @ $V_{GS} = -10V$, $I_D = -0.6A$

$R_{DS(ON)} \leq 1.1 \Omega$ @ $V_{GS} = -4.5V$, $I_D = -0.6A$

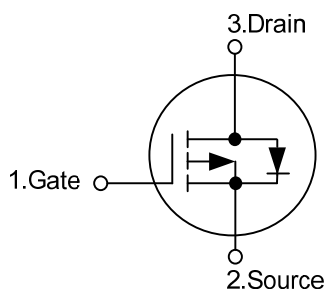
* High switching speed

* Low input capacitance



SOT-23-3
(JEDEC TO-236)

SYMBOL



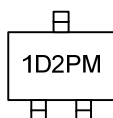
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
UT1D2P10ML-AE2-R	UT1D2P10MG-AE2-R	SOT-23-3	G	S	D	Tape Reel

Note: Pin Assignment: G: Gate S: Source D: Drain S: Source

UT1D2P10MG-AE2-R		(1) Packing Type	(1) R: Tape Reel
		(2) Package Type	(2) AE2: SOT-23-3
		(3) Green Package	(3) G: Halogen Free and Lead Free, L: Lead Free

MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_A=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DS}	-100	V
Gate-Source Voltage		V_{GS}	± 20	V
Drain Current	Continuous	I_D	-1.2	A
	Pulsed (Note 2)	I_{DM}	-3.6	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	2	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3.3	V/ns
Power Dissipation		P_D	0.3	W
Junction Temperature		T_J	+150	$^{\circ}\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L = 1\text{mH}$, $I_{AS} = -2\text{A}$, $V_{DD} = -70\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$

4. $I_{SD} \leq -1.2\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	416	$^{\circ}\text{C}/\text{W}$

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

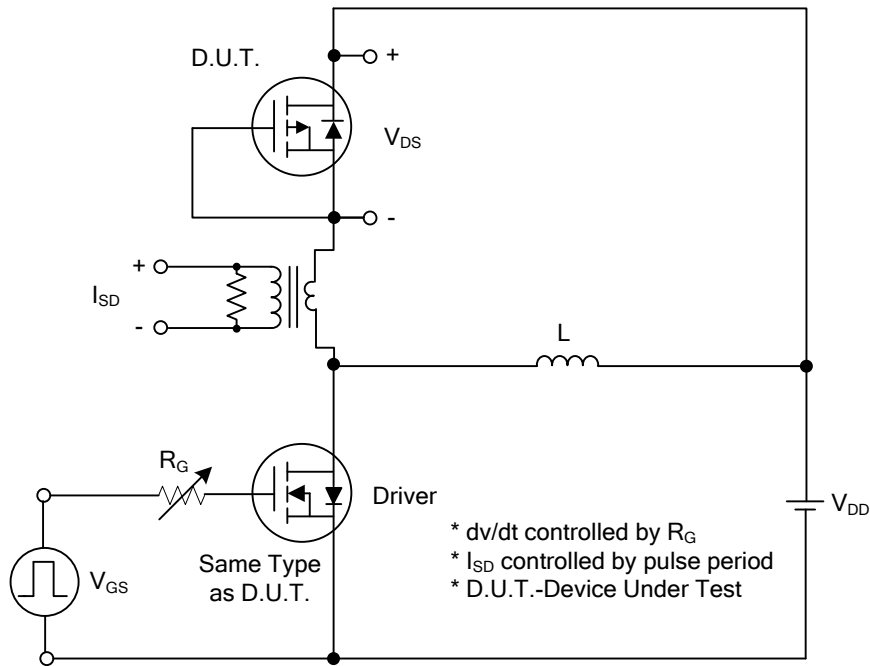
■ ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =-250μA	-100			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =-100V, V _{GS} =0V			-1	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V			±100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =-250μA	-1.0		-3	V
Drain-Source On-State Resistance (Note 1, 2)	R _{DS(ON)}	V _{GS} =-10V, I _D =-0.6A			0.95	Ω
		V _{GS} =-4.5V, I _D =-0.6A			1.1	Ω
DYNAMIC PARAMETERS						
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =-25V, f=1.0MHz		338		pF
Output Capacitance	C _{OSS}			21		pF
Reverse Transfer Capacitance	C _{RSS}			13		pF
SWITCHING CHARACTERISTICS						
Total Gate Charge	Q _G	V _{DS} =-80V, V _{GS} =-10V, I _D =-1.2A (Note 1, 2)		12		nC
Gate-Source Charge	Q _{GS}			2		nC
Gate-Drain Charge	Q _{GD}			2		nC
Turn-ON Delay Time	t _{D(ON)}	V _{DS} =-50V, V _{GS} =-10V, I _D =-1.2A, R _G =3Ω (Note 1, 2)		5		ns
Turn-ON Rise Time	t _R			17		ns
Turn-OFF Delay Time	t _{D(OFF)}			13		ns
Turn-OFF Fall Time	t _F			19		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Continuous Drain-Source Diode Forward Current (Note 1, 2)	I _S				-1.2	A
Diode Forward Voltage (Note 1)	V _{SD}	I _F =-1.2A, V _{GS} =0V			-1.4	V
Body Diode Reverse Recovery Time (Note 1)	t _{rr}	I _S =-1.2A, V _{GS} =0V, dI _F /dt =100A/μs		24		ns
Body Diode Reverse Recovery Charge	Q _{rr}			30		nC

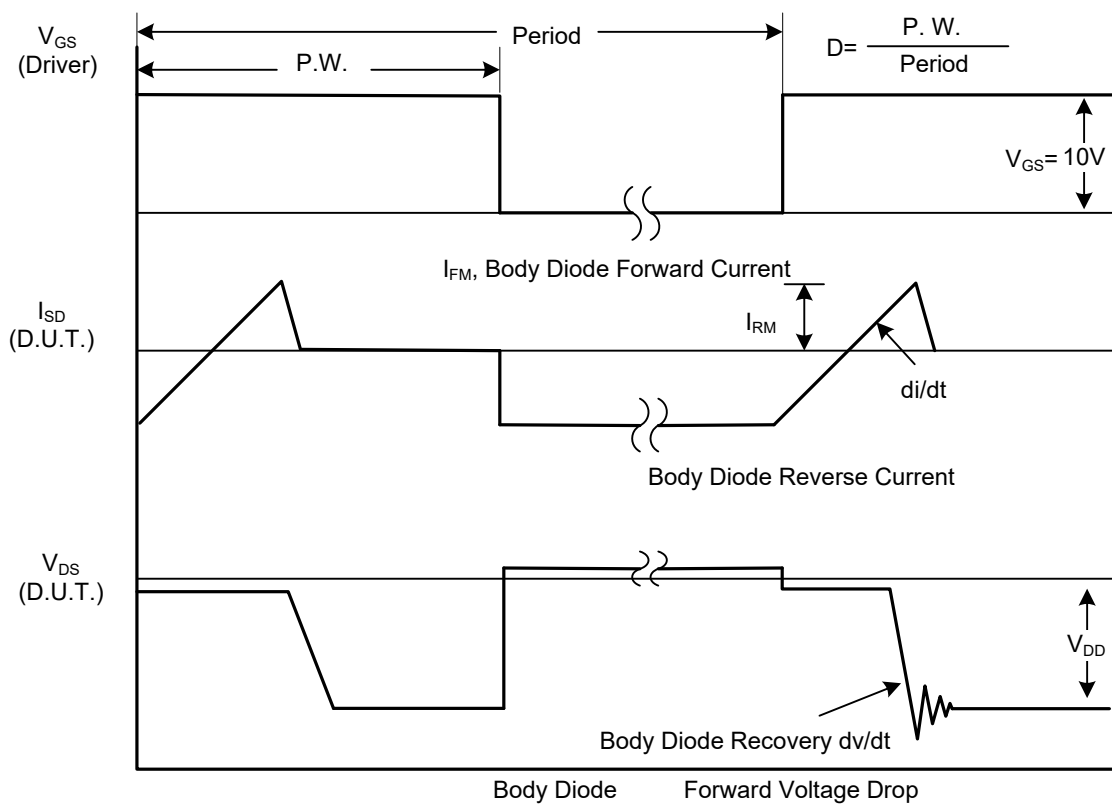
Notes: 1. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

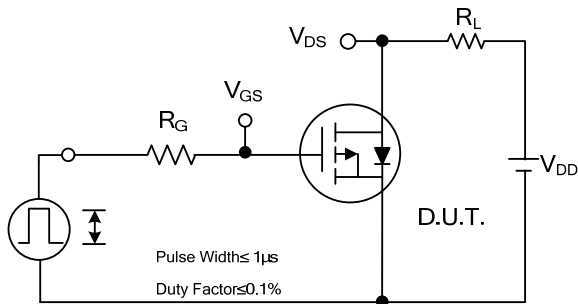


Peak Diode Recovery dv/dt Test Circuit

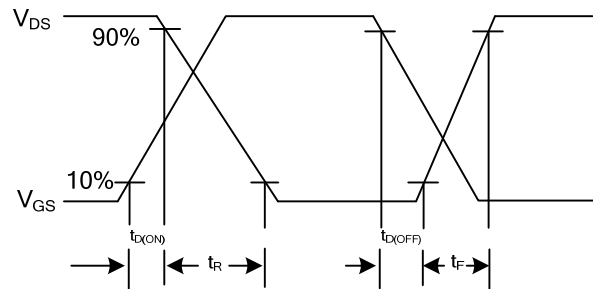


Peak Diode Recovery dv/dt Waveforms

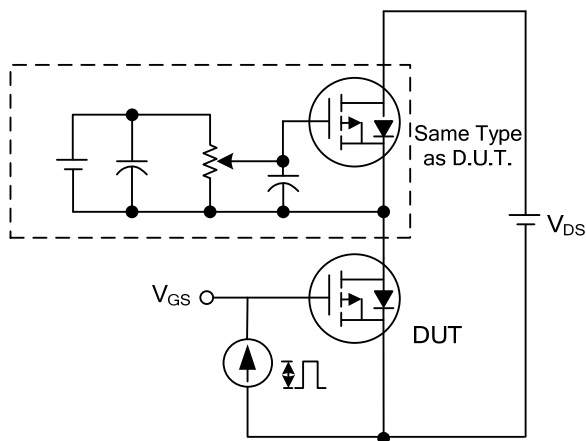
■ TEST CIRCUITS AND WAVEFORMS



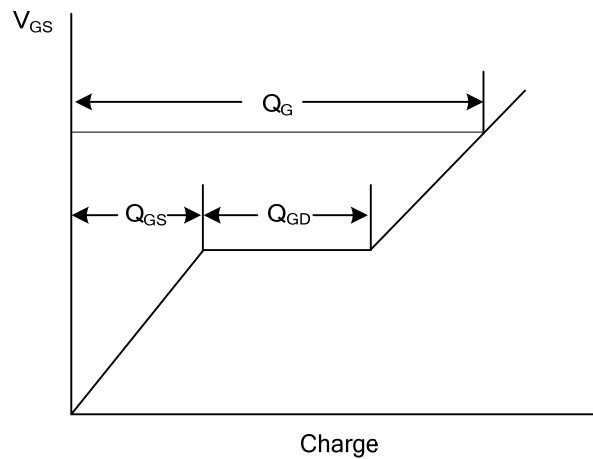
Switching Test Circuit



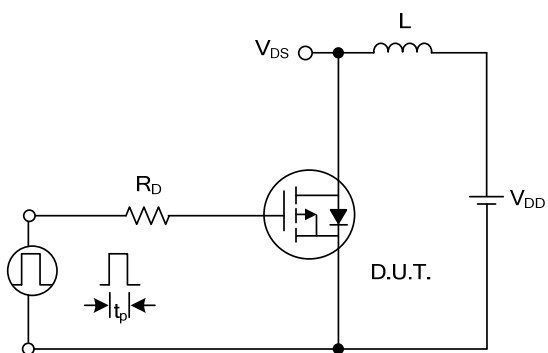
Switching Waveforms



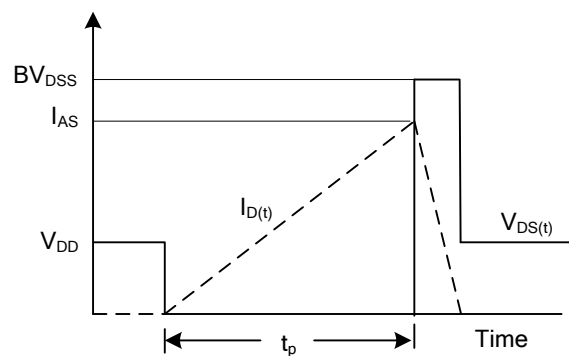
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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